

Notice of References Cited	Application/Control No. 10/578,952		Applicant(s)/Patent Under Reexamination LE FEVRE ET AL.	
	Examiner JUNIOR O. MENDOZA		Art Unit 2423	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,883,621 A	03-1999	Iwamura, Ryuichi	725/37
*	B	US-2003/0202776 A1	10-2003	Kendall et al.	386/94
*	C	US-6,707,508 B1	03-2004	Mears et al.	348/731
*	D	US-7,039,936 B1	05-2006	Inoue et al.	725/59
*	E	US-2006/0204208 A1	09-2006	Mears et al.	386/046
*	F	US-2006/0291799 A1	12-2006	Mears et al.	386/083
*	G	US-7,199,835 B2	04-2007	Takano et al.	348/558
*	H	US-7,289,482 B2	10-2007	Jang et al.	370/341
*	I	US-7,305,504 B2	12-2007	Hong et al.	710/104
*	J	US-7,409,480 B2	08-2008	Hata et al.	710/104
*	K	US-7,448,060 B2	11-2008	Takano et al.	725/80
*	L	US-7,596,640 B2	09-2009	Sakai, Hiroki	710/31
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	W	
	X	

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